



PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Re the Application of

Yasuji SEKO et al.

Application No.: 10/660,582

Filed: September 12, 2003

Docket No.: 117159

For: POSITION MEASUREMENT SYSTEM

INFORMATION DISCLOSURE STATEMENT

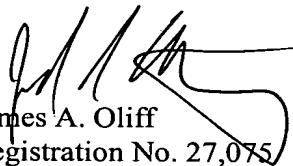
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the reference(s) listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference(s) be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- 2. Relevance of the non-English language reference is discussed in the present specification. (Ref. 1)

Respectfully submitted,



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Date: December 1, 2003

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| <p>DEPOSIT ACCOUNT USE AUTHORIZATION Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461</p> |
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Sheet 1 of 1

| Form PTO-1449 (REV. 8-83) | | US Dept. of Commerce PATENT & TRADEMARK OFFICE | ATTY DOCKET NO. 117159 | APPLICATION NO. 10/660,582 | | |
|---|---|---|---------------------------|-------------------------------|-----------------|-----------|
| INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary) | | | | | | |
| | | APPLICANTS Yasuji SEKO et al. | | | | |
| | | FILING DATE September 12, 2003 | | | | |
| U.S. PATENT DOCUMENTS | | | | | | |
| EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB CLASS |
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| OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.) | | | | | | |
| | 1 | "Light Interference Lens Method" Yasuji Seko; 63 rd Autumn Meeting of the Japan Society of Applied Physics and Related Societies, Proceedings (September 2002), 24p-ZN-7 | | | | |
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| EXAMINER | | | | | DATE CONSIDERED | |
| Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | | | | | | |